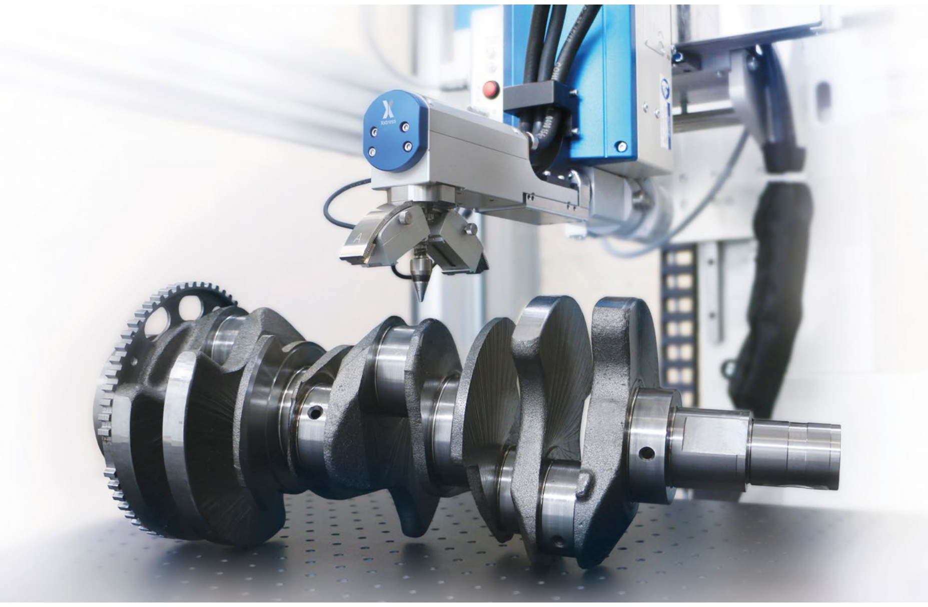
Xstress G3

X-ray diffractometer

X-ray diffractometer Xstress G3, with modifiable movements gives access to confined spaces and complex geometries. Advances in design and construction provide enhanced reliability and function in a truly portable residual stress and retained austenite analyzer.

Technical specifications

- ✓ Non-destructive
- ✓ Suitable for laboratory, factory and field use
- ✓ Quick assembly, ready to use in 10 minutes
- ✓ Easy replacement of X-ray tube (Cr, Cu, Co, Fe, V, Ti, Mn) which enables measuring different materials
- ✓ Three measurement distances as standard: 50, 75 and 100 mm
- ✓ Two NMOS position sensitive detectors
- ✓ Instantly adjustable 2θ-angle
- ✓ XTronic software for running the measurement and calculating residual stresses and retained austenite content (optional)
- ✓ d-$\sin^2\chi$ and Ω-measurement modes as a standard



Dimensions

Depth	574 mm	22.60 in
Width	712 mm	28.03 in
Height	492 mm	19.37 in
Weight	16 kg	35.3 lbs

stresstech

Measure for success

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